

# CMOS Fast Transient Low-Dropout Regulator

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**Abstract**— In this paper a fast transient response CFA-based low-dropout regulator (LDO) is introduced. The circuit is stable for 0-100mA output load current and a 1 $\mu$ F output capacitor without any internal compensation. The CFA consists of a voltage follower with output local current-current feedback based on a level-shifted flipped voltage follower (LSFVF) which is instrumental to achieve high regulation and fast transient response. The inverting output buffer stage of the CFA together with current-mirror-based driving of the pass transistor results in high PSRR. Full transistor-level simulation results for an AMS 0.35 $\mu$ m CMOS process design reveal that the proposed LDO dissipates 58 $\mu$ A quiescent current at no-load condition and in worst case conditions has a current efficiency of 99.8%. For a 1 $\mu$ F output capacitor, the maximum output voltage variation to a 0-100mA load transient with rise and fall time of 10 and 100ns is only 2.5mV, and the PSRR is smaller than -58dB over the entire load current range.

**Keywords**—fast transient; level-shifted flipped voltage follower; low-dropout

## I. INTRODUCTION

Power management circuits are very essential in battery-operated electronic systems like cellular phones and PDAs in order to reduce the standby power consumption and increase the battery life. Low-dropout regulators (LDOs) are widely used alone in many integrated power management circuits but also used as post regulators of switching converters, as they can provide wideband regulated low noise supply voltage for noise-sensitive analog and RF loads. A conventional LDO consists of an error amplifier for detecting the error between the reference and output voltage, a pass transistor controlled by the error amplifier for delivering current to the load, a feedback network, and an output capacitor. Several performance indexes should be carried out when designing an LDO, such as closed-loop stability for a wide range of loads, static regulation in front of input voltage and load variations, and fast rejection of abrupt transient load variations [1, 2]. Different techniques have been proposed up to now for stability, such as pole-zero cancellation method [2] and pole-splitting schemes [3-5]. An internal zero generated through a voltage-controlled current source (VCCS) is used in [6] for frequency response compensation and enhanced stability. Dual-loop feedback in the form of using a current buffer approach in the compensation network is another way to improve transient response and stability, which was proposed in [7-10]. LDOs based on the flipped voltage follower (FVF) were introduced in [11, 12]. Current-mode LDOs have been proposed in [13, 14], in which the pass

transistor operates like a voltage-controlled current source. With this method, the LDO dropout is minimized and high power supply ripple rejection (PSRR) can be achieved.

In previously reported LDOs, voltage-mode operational amplifiers are used as error amplifiers, thereby limiting the regulator performance due to their fixed gain-bandwidth product and limited slew rate. These limitations affect the LDO stability and transient response. Complementarily, a strategic design target is to avoid on-chip compensating capacitors, which occupy a large chip area thus achieving the required stability using only external off-chip load capacitance [3]. With regard to the above considerations, in this paper a CMOS fast transient LDO regulator based on a current feedback amplifier (CFA) exhibiting fast transient stable performance is presented. Section II describes the proposed LDO architecture. In section III, the CFA design criteria of the LDO are presented. Finally, transistor-level characterization and conclusions are given in sections IV and V, respectively.

## II. PROPOSED LDO ARCHITECTURE

The block diagram of the proposed LDO is shown in Fig. 1. The control mechanism of the pass transistor in the LDO is accomplished by a CFA which is based on the conjunction of an open-loop voltage follower with current copying capability and an inverting output buffer. The output signal is transferred to the inverting input of the CFA (X node, which has very low impedance), through the feedback network, and is compared with the reference voltage. This comparison result is amplified through the transimpedance gain of the CFA thereby controlling the gate of the pass transistor. Very low impedance at the inverting input of the CFA is the key to achieve high regulation and fast transient response. In addition, if the slew rate at the gate of the pass transistor is much slower than the gain-bandwidth product, transient voltage spikes appear at the output voltage node during fast load transient. So, due to the fact that CFAs have excellent performance in terms of bandwidth and slew rate, this issue can be eliminated in the proposed LDO and fast transient response with minimum slew rate limiting can be achieved.

The transistor level schematic of the proposed LDO is shown in Fig. 2. The circuit is composed of a CFA (a class AB voltage follower,  $M_1$ - $M_{12}$ , plus an inverting output buffer,  $M_{13}$ ,  $M_{14}$ ), a pass transistor  $M_p$ , and a feedback network  $R_1$  and  $R_2$ . In order to achieve high input impedance, the

reference voltage  $V_{ref}$  is fed to the circuit through a simple unity-gain amplifier, which is not shown in Fig. 2. Also, this ensures that there is no DC current drained from the reference voltage. Since the bias conditions and sizes of transistor pairs  $M_1$ - $M_3$  and  $M_2$ - $M_4$  are equal, it is derived that  $V_{SG1}=V_{SG3}$ ,  $V_{GS2}=V_{GS4}$  and hence the generated reference voltage through the unity-gain amplifier appears at the output node. The mechanism of voltage regulation in the event of a load current transient is discussed in the following. In case that the load current increases, the voltage at the output capacitor drops. Thus, the source terminal voltage of  $M_3$  and  $M_4$ , and hence their drain terminal voltage will be decreased, this voltage reduction being transferred to the gate voltage of  $M_7$  and  $M_8$  through  $M_5$  and  $M_6$ , respectively. This voltage reduction instantaneously increases the current through transistors ( $M_7$ ,  $M_9$ ,  $M_{11}$ ) and decreases the current through ( $M_8$ ,  $M_{10}$ ,  $M_{12}$ ). As a result, the gate voltage of  $M_{13}$  increases, which causes the gate voltage of  $M_p$  to decrease so that more drain current is sourced to the load as well as to the output capacitor. Therefore, the output voltage will be increased. An analogous mechanism occurs when the load current decreases.

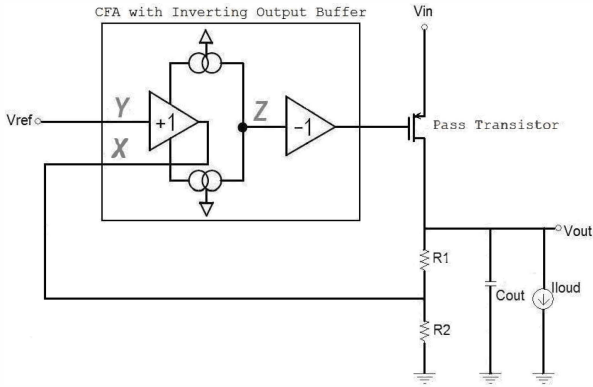


Figure 1. Proposed LDO architecture.

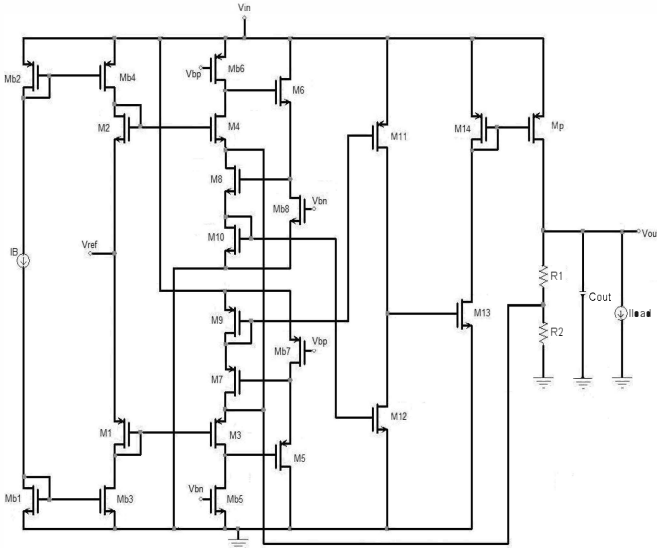


Figure 2. Schematic of the proposed LDO.

### III. DESIGN CONSIDERATIONS

The CFA which is used in the proposed LDO consists of an input buffer with current copying capability. Conventional buffers in CMOS processes have output impedances around  $1/g_m$ , which is in the range of kilo ohms. In this structure, a pre-compensated level shifter flipped voltage follower (LSFVF) with local current-current feedback is used as an input voltage buffer with current copying capability aiming to obtain very low output impedance in the range of ohms, and achieving high regulation and fast transient response. Because of the use of current-current feedback, the output impedance of the LSFVF formed by transistors ( $M_3$ ,  $M_5$ ,  $M_7$ ) and ( $M_4$ ,  $M_6$ ,  $M_8$ ) is given by

$$R_{o,LSFVF} = \frac{1}{g_{m3}g_{m7}r_{ds3}} \parallel \frac{1}{g_{m4}g_{m8}r_{ds4}} \quad (1)$$

where  $g_{mi}$  and  $r_{dsi}$  are the transconductance and output impedance of transistor  $M_i$ , respectively. The AC output impedance of the input voltage buffer is under 32 ohms, which is a very low value for a MOS technology. Regulation and transient response of the LDO is proportional to its loop-gain, and so by increasing the loop-gain, high regulation and fast transient response can be achieved. The main advantage of using a LSFVF is an increase of the loop-gain ( $A\beta$ ) of the CFA-based LDO, where  $A$  is the transimpedance gain of the CFA and  $\beta$  is the feedback factor, which is equal to the transconductance at the inverting input of the CFA (X node). By using local feedback, the feedback factor  $\beta$  will be increased from  $g_{mi}$  to  $g_{mi}g_{mj}r_{dsi}$ , causing an increase in the loop-gain and hence an improvement of the regulation and transient response without stability degradation.

Transistors  $M_{13}$  and  $M_{14}$  implement the inverting output buffer of the CFA used to generate the negative feedback loop. In addition, transistor  $M_{14}$  with pass transistor  $M_p$  forms a current-mode control for the gate of pass transistor and so  $M_p$  works as a voltage-controlled current source, operating in saturation region. Therefore, its output impedance ( $r_{dsp}$ ) is high, which is key to obtain high PSRR. In typical LDOs, the power supply ripple to output transfer function is approximated by [15]

$$\frac{\partial V_{out}}{\partial V_{dd}} = \left[ \frac{1-A_p}{A\beta} + \frac{1}{g_{mp}r_{dsp}} \frac{1}{A\beta} \right] \quad (2)$$

where  $A_p$  is the gain from the power supply  $V_{dd}$  ( $V_{in}$  in Fig. 2) to the gate of the pass transistor,  $A$  is the gain from  $V_{ref}$  to the gate of pass transistor,  $g_{mp}$  and  $r_{dsp}$  are the transconductance and the output impedance of the pass transistor, and  $\beta$  is the feedback factor. As it can be seen, one way to improve PSRR is to increase the gain of the CFA. An alternative approach is to design the circuit such that  $A_p$  is close to 1. This means that the gate voltage of the pass transistor  $M_p$  should be close to the supply voltage and track

the source terminal voltage of  $M_p$ , which is connected to the supply voltage. In this design, transistors  $M_{13}$  and  $M_{14}$  form a subtractor stage. This stage feeds the supply noise directly into the feedback loop and modulates the gate of  $M_p$  with respect to its source terminal. Since the output impedance of transistor  $M_{13}$ ,  $r_{ds13}$ , is higher than the diode-connected transistor  $M_{14}$ ,  $1/g_{m14}$ , the gate terminal voltage of  $M_p$  follows its source terminal. So, the drain current variation of the pass transistor due to the supply voltage noise will be reduced and the output node will be less sensitive to the supply noise.

#### IV. CIRCUIT CHARACTERIZATION

The proposed LDO topology has been designed and characterized in Cadence in an AMS 0.35 $\mu$ m CMOS process. It does not require any compensation capacitor and is stabilized by an output capacitor in the range of 600nF to 1 $\mu$ F. The LDO is designed to source a nominal output current between 0-100mA and consumes a small quiescent current of 58 $\mu$ A under no-load and 200  $\mu$ A under full-load condition, which corresponds to a worst case current efficiency of 99.8%. The measured load and line regulations are 22 $\mu$ V/mA and 11.9mV/V, respectively. The power supply ripple to output (PSR) of the LDO and its open-loop AC response with a 1 $\mu$ F output capacitor are shown in Figs. 3 and 4, respectively. The measured PSR is smaller than -58dB over the entire load current range.

Load transient response of the designed LDO with a 1 $\mu$ F output capacitor to the 0-100mA load transient with rise and fall time of 10 and 100ns is shown in Fig. 5. It is apparent that the LDO can react to fast load current changes and is stable over the entire load current with a maximum output voltage variation of only 2.5mV.

Table I provides a performance comparison between the proposed LDO and recently published designs. The figure of merit ( $FOM = T_R \times I_q / I_{load,Max}$ ) used in [11] is adopted here to compare the transient response of different LDOs by evaluating the effect of the quiescent current  $I_q$  to the load transient response time ( $T_R$ ). The  $T_R$  of the LDO is given by  $T_R = C_{out} \Delta V_{out} / I_{load,Max}$ , where  $\Delta V_{out}$  is the maximum transient output voltage variation.

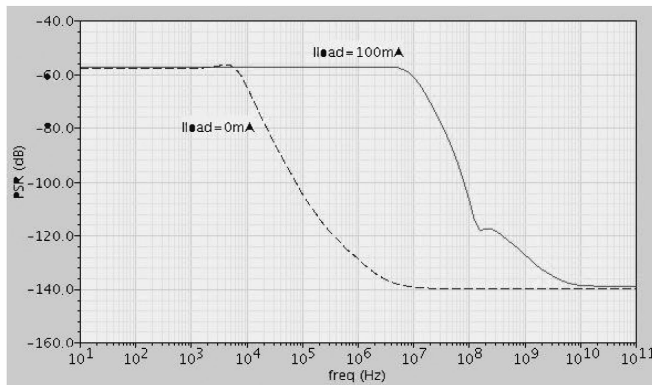


Figure 3. PSR of the proposed LDO with 1 $\mu$ F output capacitor.

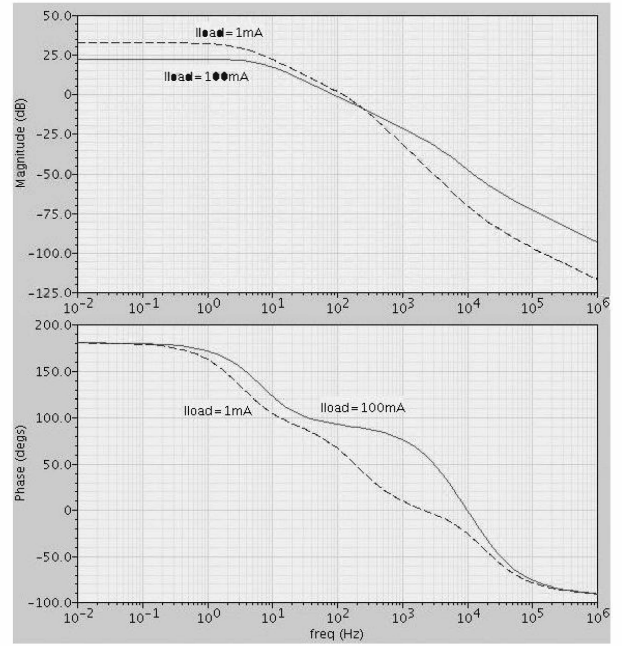


Figure 4. Open-loop AC response with 1 $\mu$ F output capacitor.

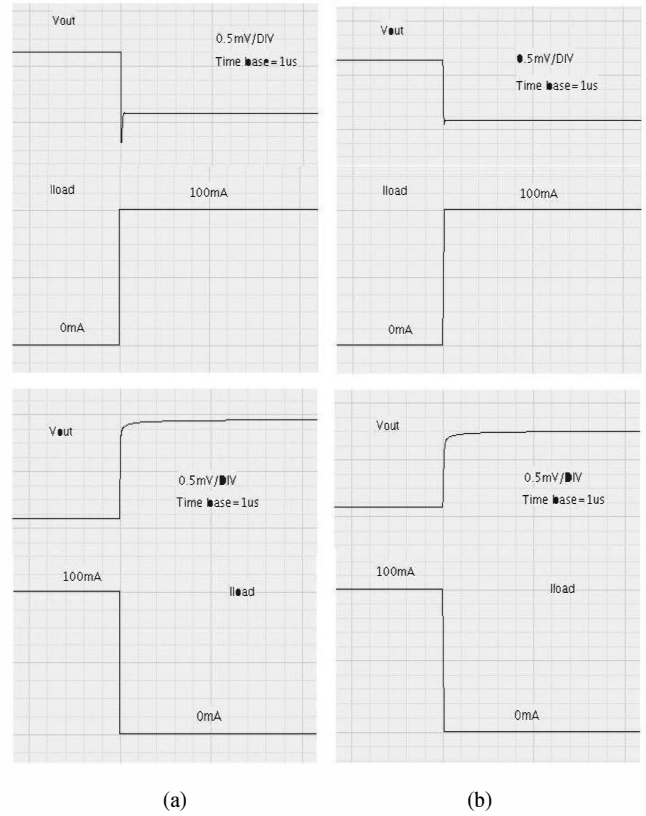


Figure 5. Load transient response with 1 $\mu$ F output capacitor (a) load transient with 10ns rise and fall time (b) load transient with 100ns rise and fall time.

TABLE I. PERFORMANCE SUMMARY AND COMPARISON WITH RECENTLY PUBLISHED WORKS

Parameter	Unit	[6]	[7]	[11]	[12]	[14]	[16]	This Work
Technology	$\mu\text{m}$	0.5	0.35	0.09	0.35	0.35	0.25	<b>0.35</b>
$I_{load,Max}$	mA	160	200	100	50	50	50	<b>100</b>
$V_{in}$	V	3.3	2-5.5	1.2	1.2-1.5	1.05-3.5	2-2.5	<b>3-5</b>
$V_{out}$	V	2.8	1.8	0.9	1	0.9	1.5-1.97	<b>2.8</b>
Output Capacitor	$\mu\text{F}$	2.2	1	0.0006	1	1	0.05	<b>1</b>
$I_q$	$\mu\text{A}$	25	20-320	6000	95	4.04-164	100	<b>58-200</b>
PSRR	dB	N.A.	>45 (0Hz-20KHz)	N.A.	N.A.	>50 (0Hz-1MHz)	43 @30KHz	<b>&gt;58</b>
$\Delta V_{out}$	mV	200	54	90	30	6.6	15	<b>2.5</b>
$T_R$	$\mu\text{s}$	2.75	0.27	0.00054	0.6	0.132	0.03	<b>0.025</b>
FOM	ns	0.43	0.027	0.032	1.14	0.0106	0.06	<b>0.0145</b>

A lower FOM implies a better transient response achieved by the LDO. By using a  $1\mu\text{F}$  output capacitor in the proposed LDO, the maximum output voltage variation is 2.5mV and  $T_R$  is equal to 0.025 $\mu\text{s}$ . Hence, as it can be observed in table I, the FOM of the proposed LDO is very comparable to the design in [14] and smaller than other reported LDOs.

## V. CONCLUSION

A current-steering fast transient response CFA-based LDO is presented. The circuit is stable for 0-100mA output load and a  $1\mu\text{F}$  output capacitor without any internal compensation capacitor. The CFA consists of an open-loop voltage follower with output local current-current feedback based on a LSFVF that is the key to achieve good regulation and fast transient response. The inverting output buffer stage of the CFA together with a current-mirror-based driving of the pass transistor results in high PSRR. Simulation results for an AMS 0.35 $\mu\text{m}$  CMOS process design reveal that the proposed LDO dissipates 58 $\mu\text{A}$  quiescent current at no-load condition and in the worst case has a current efficiency of 99.8%. With a  $1\mu\text{F}$  output capacitor, the maximum output voltage variation to the 0-100mA load transient with rise and fall time of 10 and 100ns is only 2.5mV and the PSRR is smaller than -58dB for all frequencies and over the entire load current range.

## REFERENCES

- [1] R. K. Dokania and G. A. Rincon-Mora, "Cancellation of load regulation in low dropout regulators," *Electron Lett.*, vol. 38, no. 22, pp. 1300-1302, Oct. 2002.
- [2] G. A. Rincon-Mora and P. E. Allen, "Optimized frequency-shaping circuit topologies for LDOs," *IEEE Trans. Circuits Syst. II, Analog Digital Signal Process.*, vol. 45, no. 6, pp. 703-708, Jun. 1998.
- [3] K. L. Leung and P. K. T. Mok, "A capacitor-free CMOS low-dropout regulator with damping-factor-control frequency compensation," *IEEE J. Solid-State Circuits*, vol. 38, no. 10, pp. 1691-1702, Oct. 2003.
- [4] S. K. Lau, P. K. T. Mok, and K. N. Leung, "A low-dropout regulator for SoC with Q-reduction," *IEEE J. Solid-State Circuits*, vol. 42, no. 3, pp. 658-664, Mar. 2007.
- [5] W. J. Hung, S. H. Lu, and S. I. Liu, "CMOS low dropout linear regulator with single Miller capacitor," *Electron Lett.*, vol. 42, no. 4, pp. 216-217, Feb. 2006.
- [6] C. K. Chava and J. Silva-Martinez, "A frequency compensation scheme for LDO voltage regulators," *IEEE Trans. Circuits Syst. I*, vol. 51, no. 6, pp. 1041-1050, Jun. 2004.
- [7] M. Al-Shyoukh, H. Lee, and R. Perez, "A transient-enhanced low-quiescent current low-dropout regulator with buffer impedance attenuation," *IEEE J. Solid-State Circuits*, vol. 42, no. 8, pp. 1732-1742, Aug. 2007.
- [8] G. A. Rincon-Mora, "Active capacitor multiplier in Miller-compensated circuits," *IEEE J. Solid-State Circuits*, vol. 35, no. 1, pp. 26-32, Jan. 2000.
- [9] W. Chen, W. H. Ki, and P. K. T. Mok, "Dual-loop feedback for fast low dropout regulators," *Proc. IEEE 32nd Power Electron. Specialists Conf. (PSEC'01)*, vol. 3, Jun. 2001, pp. 1265-1269.
- [10] R. J. Milliken, J. Silva-Martinez, and E. Sanchez-Sinencio, "Full on-chip CMOS low-dropout voltage regulator," *IEEE Trans. Circuits Syst. I*, vol. 54, no. 9, pp. 1879-1890, Sept. 2007.
- [11] P. Hazucha, T. Karnik, B. Bloechel, C. Parsons, D. Finan, and S. Borkar, "Area-efficient linear regulator with ultra-fast load regulation," *IEEE J. Solid-State Circuits*, vol. 40, no. 4, pp. 933-940, Apr. 2005.
- [12] T. Y. Man, K. L. Leung, C. Y. Leung, P. K. T. Mok, and M. Chan, "Development of single-transistor-control LDO based on flipped voltage follower for SoC," *IEEE Trans. Circuits Syst. I*, vol. 55, no. 5, pp. 1392-1401, Jun. 2008.
- [13] G. Thiele and E. Bayer, "Current-mode LDO with active dropout optimization," *Proc. IEEE 36th Power Electron. Specialists Conf. (PSEC'05)*, Jun. 2005, pp. 1203-1208.
- [14] Y. Hei and W. H. Ki, "A 0.9V 0.35 $\mu\text{m}$  adaptively biased CMOS LDO regulator with fast transient response," *Proc. IEEE Int. Solid-State Circuits Conf. (ISSCC'08)*, Feb. 2008, pp. 442-443.
- [15] S. K. Hoon, S. Chen, F. Maloberti, J. Chen, and B. Aravind, "A low noise, high power supply rejection low dropout regulator for wireless system-on-chip applications," *Proc. IEEE Custom Integrated Circuits Conf.*, Sept. 2005, pp. 759-762.
- [16] W. Oh and B. Bakkaloglu, "A CMOS low-dropout regulator with current-mode feedback buffer amplifier," *IEEE Trans. Circuits Syst. II*, vol. 54, no. 10, Oct. 2007.